Gamma Radiation Induced Space Charge Sign Re-inversion in Proton Irradiated High Resistivity CZ Si Detectors

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Introduction

• [O] in CZ Si: in the 10¹⁸'s /cm³

Comes naturally from wafer manufacture process Resistivity ≤100 Ω-cm

Thermal donor (TD) a problem

- Magnetic CZ technology now available: High [O] High resistivity ≥1000 Ω-cm : almost detector grade
- SCSI (from + to -) still observed in proton irradiated MCZ Si Detectors, although at much higher fluence
- Positive space charge induced in MCZ Si detectors after gamma radiation (+ to ++)
- Can space charge sign re-invert (SCSRI) back to positive with gamma radiation on p-irradiated, SCSI MCZ Si detectors From – to +)?
- What is field distribution (will DJ/DP still preserve)?

Experimental

• Samples

Control FZ (CFZ) samples and some MCZ samples processed together by Univ. of Helsinki, and some MCZ samples were processed by BNL Oxidation: 8+5 hours in O₂ at 1050 °C, all diodes are p⁺/n/n⁺ junctions

Wafer #	Туре	Resistivity (Ω-cm)	Thickness (µm)
1	CFZ	3000	520
A, B, 3	MCZ	1200	380

Various square diodes of 0.36 cm² each from each wafer were used

Radiation

Neutrons: <E>=1 MeV; fluence: 0 to 2.9x10¹⁴ n/cm² Protons: 10 MeV and 20 MeV; fluence: 0 to 1.2x10¹⁴ p/cm² 60Co gamma: E = 1.25 MeV; Dose rate: 0.5 Mrad/hr; Dose range: 0-1.2 Grad

Measurements

TCT measurements using a red laser

Negative SC build-up for control FZ Si detectors is: -1.82x10⁹ x Dose Positive SC build-up for Oxy Si detectors is: 4.1 x10⁸ Dose Positive SC build-up for MCZ Si detectors is: 2.9 x10⁹ x Dose, about 8 times higher



Full depletion voltage vs. n-fluence

Full Depeltion Voltage



Comparison of N_{eff} vs. 1 MeV equivalent n-fluence between neutron and proton radiations



1 MeV equivalent n- Fluence (1E13 n/cm2)

Neff (1/cm3)

O CZ Si detectors are slightly more rad-hard than FZ ones with n-rad β_{CZ} (b in the figure) is about 23% less than β_{FZ}
O CZ Si detectors are much more rad-hard than FZ ones with p-rad β_{CZ} is about 1/5 of β_{FZ} and is about ½ of β_{OXY} SCSI fluence is 3 time higher than that of FZ

Comparison and summary of radiation induced detects

$N_{eff} = \beta_{\gamma,n,n_{eq}} \cdot \Phi_{\gamma,n,orn_{eq}}, (\Phi_{\gamma} \text{ in Mrad}, \Phi_n \text{ and } \Phi_{n_{eq}} \text{ in } n_{eq}/cm^2)$						
Detector Type	Gamma $\beta_{\gamma} (1/Mrad-cm^3)$	$\frac{n (1 \text{ MeV})}{\beta_n (1/n_{eq}\text{-}cm)}$	Proton $\beta_{n_{eq}} (1/n_{eq}\text{-cm})$	Normalized Rad-hard factor		
CFZ	-1.82x10 ⁹	-0.022		1		
MCZ	2.92 x10 ⁹	-0.017	-0.0045	5		
(old) FZ	-8.0x10 ⁹	-0.023	-0.022	1		
HTLT oxygenated	4.1x10 ⁸	-0.023	-0.0094	2.4		

ntroduction rate of stable defects

Introduction rate of reverse anneal generated defects

$N_{eff}^{rev} = \beta_{rev, n or n_{eq}} \cdot \Phi_{n or n_{eq}}, (\Phi_n \text{ and } \Phi_{n_{eq}} \text{ in } n_{eq}/cm^2)$							
Detector Type	n (1 MeV) β_n^{rev} (1/n _{eq} -cm)	Proton $\beta_{n_{eq}}^{rev}$ (1/ n _{eq} -cm)	Normalized Rad- hard factor				
CFZ	-0.062		1				
MCZ	-0.050	-0.0096	5-7				
(old) FZ	-0.073		1				

- With higher [O], MCZ Si has more un-activated TD's
 - **Produced during the TD killing process**
- Gamma radiation activates those un-activated TD's, giving rise to the higher positive SC build-up rate
- This positive SC build-up may also happen in charged particle irradiated MCZ Si detectors, giving possibility of compensating regular negative SC ---- improvement of rad-hardness
- The degree of this improvement in rad-hardness may depend type of particle radiation
- MCZ Si detectors are also more rad-hard than CFZ Si detectors in reverse annealing



Increase in the field of the front junction clearly observed Double peak field still exists, but back peak smaller --- space charge almost becomes positive (expect to see SCSRI at next dose of 450 Mrad)



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After 454 Mrad, Space charge Sign re-inverted Double peak field still exists



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#A-3-15, MCZ, 380 μm, 5.9x10¹³ p/cm² (10 MeV), 9 month RTA + gamma radiation (454 Mrad) laser (red) back



After 662 Mrad, Space charge Sign re-inverted clearly seen



#A-3-15, MCZ, 380 µm, 5.9x10¹³ p/cm² (10 MeV), 9 month RTA laser (red) front

After 662 Mrad, Space charge Sign re-inverted clearly seen Double peak field still barely exists



#A-3-15, MCZ, 380 μm, 5.9x10¹³ p/cm² (10 MeV), 9 month RTA + gamma radiation (662 Mrad) laser (red) back

After 662 Mrad, Space charge Sign re-inverted clearly seen Double peak field still exists





Neutron radiation + gamma radiation in MCZ Si detectors #3-3-1, MCZ, 380 µm, 8.23x10¹³ n/cm², 9 month RTA + gamma radiation (662 Mrad)

laser (red) back



#3-3-1, MCZ, 380 μm, 8.23x10¹³ n/cm², 9 month RTA + gamma radiation (662 Mrad) laser (red) back



Summary

o Positive space charge built-up observed in p and n – irradiated MCZ Si detectors after gamma radiation

o SCSRI was achieved at the high dose 454 Mrad in a low fluence proton irradiated MCZ Si detector

o No SCSRI yet for low fluence n-irradiated MCZ Si detector at the highest dose in this study, but positive space charge is building-up, SCSRI expected at higher doses

o Up to the highest dose in this study, the DJ/DP field distribution is still preserved

o No SCSRI observed in control FZ Si detectors